

TRANSMITTAL OF INFORMATION DISCLOSURE STATEMENT
(Under 37 CFR 1.97(b) or 1.97(c))Docket No.
3834

In Re Application Of: PARTHIER, L., ET AL

Application No.	Filing Date	Examiner	Customer No.	Group Art Unit	Confirmation No.
10/590,059	08/21/2006		278		

Title: PROCESS FOR PREPARING CAF2 LENS BLANKS ESPECIALLY FOR 193 NM AND 157 NM
LITHOGRAPHY WITH MINIMIZED DEFECTS

Address to:

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450**37 CFR 1.97(b)**

1. ☒ The Information Disclosure Statement submitted herewith is being filed within three months of the filing of a national application other than a continued prosecution application under 37 CFR 1.53(d); within three months of the date of entry of the national stage as set forth in 37 CFR 1.491 in an international application; before the mailing of a first Office Action on the merits, or before the mailing of a first Office Action after the filing of a request for continued examination under 37 CFR 1.114.

37 CFR 1.97(c)

2. ☐ The Information Disclosure Statement submitted herewith is being filed after the period specified in 37 CFR 1.97(b), provided that the Information Disclosure Statement is filed before the mailing date of a Final Action under 37 CFR 1.113, a Notice of Allowance under 37 CFR 1.311, or an Action that otherwise closes prosecution in the application, and is accompanied by one of:
- ☐ the statement specified in 37 CFR 1.97(e);
- OR**
- ☐ the fee set forth in 37 CFR 1.17(p).

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(Under 37 CFR 1.97(b) or 1.97(c))

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10/590,059	08/21/2006		278		

Title: **PROCESS FOR PREPARING CA2 LENS BLANKS ESPECIALLY FOR 193 NM AND 157 NM LITHOGRAPHY WITH MINIMIZED DEFECTS**



Payment of Fee

(Only complete if Applicant elects to pay the fee set forth in 37 CFR 1.17(p))

- ☐ A check in the amount of _____ is attached.
- ☐ The Director is hereby authorized to charge and credit Deposit Account No. _____ as described below.
- ☐ Charge the amount of _____
- ☐ Credit any overpayment.
- ☐ Charge any additional fee required.
- ☐ Payment by credit card. Form PTO-2038 is attached.

WARNING: Information on this form may become public. Credit card information should not be included on this form. Provide credit card information and authorization on PTO-2038.

Certificate of Transmission by Facsimile*

I certify that this document and authorization to charge deposit account is being facsimile transmitted to the United States Patent and Trademark Office (Fa

(Date)

Signature

Typed or Printed Name of Person Signing Certificate

Certificate of Mailing by First Class Mail

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to "Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450" [37 CFR 1.8(a)] on

10/19/2006

(Date)

Signature of Person Mailing Correspondence

MICHAEL J. STRIKER

Typed or Printed Name of Person Mailing Certificate

*This certificate may only be used if paying by deposit account.

Dated: 10/19/2006

CC:

UNITED STATES PATENT AND TRADEMARK OFFICE

Examiner:.

Group:

Attorney Docket # 3834

Applicant(s): PARTHIER, L., ET AL

Serial No.: 10/590,059

Filed: 08/21/2006

For: PROCESS FOR PREPARING CAF2 LENS...

**INFORMATION DISCLOSURE STATEMENT**

October 19, 2006

Honorable Commissioner of Patents
and Trademarks
Washington, D.C. 20231

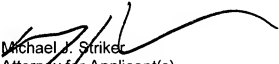
S I R S:

- ☒ In accordance with the Duty of Disclosure, Applicant(s) submit(s) herewith a copy of Foreign Search Report in a counterpart application and copies of the reference(s) indicated therein.
- ☒ In the event that the Foreign Search Report is in a foreign language, a translation thereof is herewith submitted.
- ☒ Attached hereto is a FORM PTO 1449 listing the references.
- ☒ Attached hereto is a copy of a reference cited in the specification of the application as filed. The specification itself recites the relevance of these documents, and pursuant to M.P.E.P. Section 609 A (3) this represents an acceptable Statement of Relevancy. The reference(s) appear(s) at the following page(s) and line(s) of the specification: Pg 1 Lines 32-42, Pg 2 Lines 1-4, Pg 2 Lines 4-7, Pg 2 Line 25, Pg 2 Line 26, Pg 2 Line 26, Pg 2 Lines 26- 27, Pg 3 26-28.
- ☐ Applicant petitions for consideration of this Information Disclosure Statement since it is being submitted after receipt of an office action. It is respectfully requested that the required fee be charged to the account of the undersigned: 19-4675.

Page 2 of 2

- ☐ Attached hereto are copies of references cited which may be pertinent to this application. Since the references are in the English language, no statement of relevancy is submitted.
- ☐ Attached hereto is a copy of the Office Action issued in the corresponding German and European applications, together with a translation thereof and copies of the references cited therein. A list of the cited references is also attached.
- ☐ Attached hereto copies of references cited which may be pertinent to this application. An English translation of the reference is also attached.
- ☐ Attached hereto is a Statement of Relevancy and copies of references cited therein.
- ☒ Relevancy is indicated in an English language abstract or an English language equivalent attached hereto.

Respectfully submitted,


Michael J. Striker
Attorney for Applicant(s)
Reg. No. 27233

Receipt date: 10/23/2006

ATTY DOCKET NO.

3834

APPLICATION NO.

10590059

GAU: 1792

INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

APPLICANT(S)

PARTHIER, L., ET AL

FILING DATE

08/21/2006

GROUP ART UNIT

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	6,364,946	04/02/2002	STAEBLEIN ET AL			

U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	2004/0021803	02/05/2004	MOERSEN ET AL			
	2003/0221610	12/04/2003	GARIBIN ET AL			
	2003/0089307	05/15/2003	WEHRHAN ET AL			
	2003/0093307	06/005/2003	KANDLER ET AL			

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
	10 2004 008 754	09/08/2005	DE (ENGLISH ABSTRACT)			✓	
	10 2004 008 753	09/08/2005	DE (ENGLISH ABSTRACT)			✓	
	10 2004 008 752	09/08/2005	DE (ENGLISH ABSTRACT)			✓	
	100 10 485	09/13/2001	DE				✓

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

		G. GRABOSCH, K. KNAPP, E. MOERSEN: "STATUS OF THE CAF2 PROGRAM AT SCHOTT LITHOTEC", 2ND INTERNATIONAL SEMATECH 157NM TECHNICAL DATA REVIEW MEETING, MAY 2002.
		G. GRABOSCH, K. KNAPP, L. PARTHIER, TH. WESTERHOFF, E. MOERSEN: "CALCIUM FLUORIDE QUALITY IMPROVEMENTS SUPPORT AVAILABILITY OF FIRST F2 LITHOGRAPHY TOOLS", 3RD INTERNATIONAL SEMATECH 157NM TECHNICAL DATA REVIEW MEETING, SEP. 2002

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Receipt date: 10/23/2006

ATTY DOCKET NO.
3834APPLICATION NO. GAU: 1792
1059005 10/590,059**INFORMATION DISCLOSURE CITATION**
(Use several sheets if necessary)**PARTHIER, L., ET AL**

FILING

08/21/2006

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U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	2001/0043331	11/22/2001	REBHAN			
	2005/0183659	08/25/2005	STAEBLEIN ET AL			
	2005/0204998	09/22/2005	PARTHIER ET AL			
	2003/0089306	05/15/2003	SPEIT ET AL			

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

		J. HAHN, G. GRABOSCH, L. PARTHIER, K. KNAPP; "QUALITY STATUS FOR 157NM EXPOSURE TOOLS: INTERNATIONAL SEMATECH & SELETE 4TH INTERNATIONAL SYMPOSIUM ON 157NM LITHOGRAPHY, AUG. 2003.
		L.A. SHUVALOV ED.: "MODERN CRYSTALLOGRAPHY IV" SPRINGER SERIES IN SOLID STATE SCIENCES 37, PP. 77. 1988 MJS

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U.S. PATENT APPLICATION PUBLICATIONS

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	2001/0025598	10/04/2001	STAEBLEIN ET AL			

FOREIGN PATENT DOCUMENTS

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						YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

		ENCLEA ET AL: "PRESENT AND FUTURE INDUSTRIAL METROLOGY NEEDS FOR QUALIFICATION OF HIGH-QUALITY OPTICAL MICROLITHOGRAPHY MATERIALS" PROCEEDINGS OF THE SPIE, SPIE, BELLINGHAM, VA, US, VOL. 4449, 2001, PAGES 1-6, XP002280119, ISSN: 0277-786X
		KUHN B ET AL: "COMPACTION VERSUS EXPANSION BEHAVIOR RELATED TO THE OH-CONTENT OF SYNTHETIC FUSED SILICA UNDER PROLONGED UV-LASER IRRADIATION" JOURNAL OF NON-CRYSTALLINE SOLIDS, NORTH-HOLLAND PHYSICS PUBLISHING. AMSTERDAM, NL, VOL. 330, NO. 1-3, 15 NOVEMBER 2003 (2003-11-15), PAGES 23-32, XP004471710 ISSN: 0022-3093

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10/590,059

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						YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

			PURYAYEV D T: 'INTERFEROMETRIC METHOD TO MEASURE AND TEST THE OPTICAL HOMOGENEITY OF TRANSPARENT MATERIALS" OPTICS AND LASER TECHNOLOGY, ELSEVIER SCIENCE PUBLISHERS BV, AMSTERDAM, NL, VOL. 30, NO. 3-4, 6 APRIL 1998 (1998-04-06), PAGES 235-238, XP004141896, ISSN: 0030-3992

EXAMINER

/Matthew Song/

DATE CONSIDERED

02/15/2010

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.